## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

Nobuyuki FUJIWARA et al.

International Application No.:

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Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/02102. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

10/508803

PATENT 450100-04444

## **REMARKS**

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP Attorneys for Applicants

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**Enclosures** 

Sheet 1 of 1

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